

# MEMs Parallel Plate Rheometer for Oscillatory Shear Micro Rheology Measurements

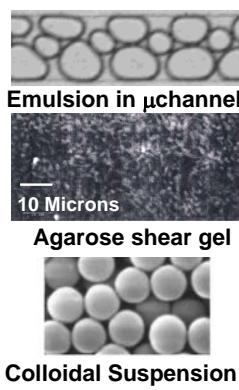
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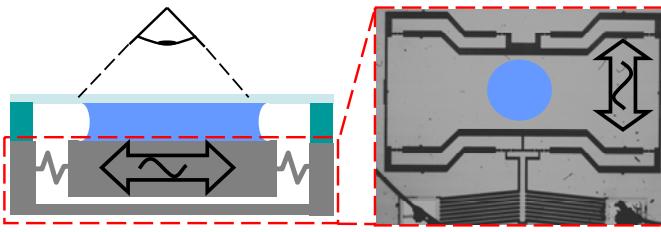
<sup>2</sup>Intelligent Systems Division, NIST, Gaithersburg, MD 20899

## Motivation

- Novel viscoelastic materials
  - Micro scale structure
- Confinement deforms structure
  - Alters rheology
- Characterization difficult
  - Small sample volumes
- Particle micro rheology does not probe entire micro structure
- Thin film measurements only elastic modulus

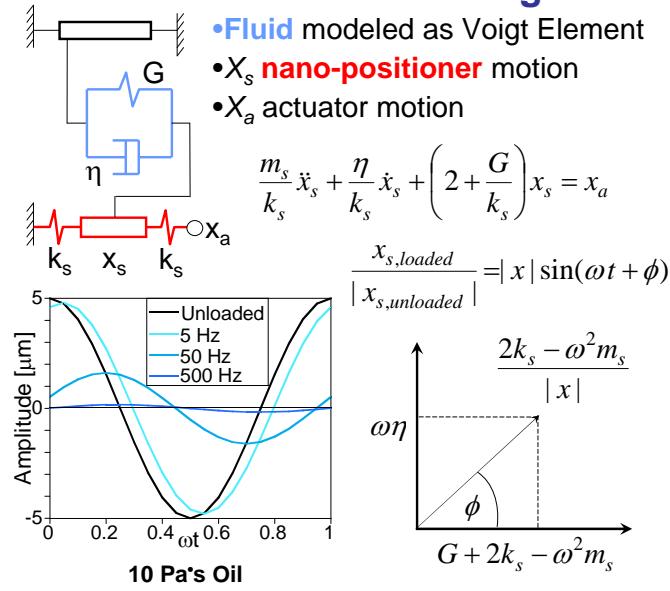


## MEMs Parallel Plate Rheometer



- 1 mm<sup>2</sup> **nano-positioner** applies sinusoidal strain
  - Thermal Actuator
  - 0.1% <  $\gamma$  < 25%
- O(1)  $\mu\text{m}$  gap set with **thin film**
- Strain applied to the entire fluid body
- Optical observation
- Storage and loss moduli at 0.5 Hz <  $f$  < 500 Hz
- Uses less than **10 nL of fluid**

## Mechanical Modeling



• Fluid modeled as Voigt Element

•  $X_s$  **nano-positioner** motion

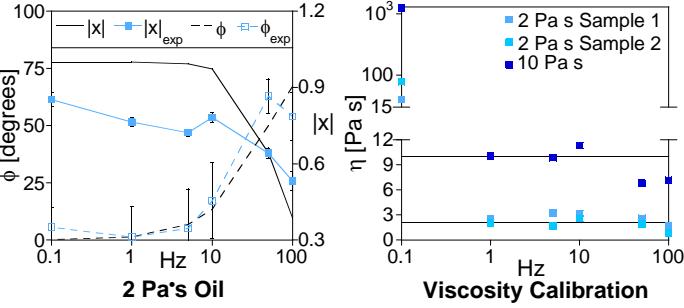
•  $X_a$  actuator motion

$$\frac{m_s}{k_s} \ddot{x}_s + \frac{\eta}{k_s} \dot{x}_s + \left( 2 + \frac{G}{k_s} \right) x_s = x_a$$

$$\frac{|x_{s,loaded}|}{|x_{s,unloaded}|} = |x| \sin(\omega t + \phi)$$

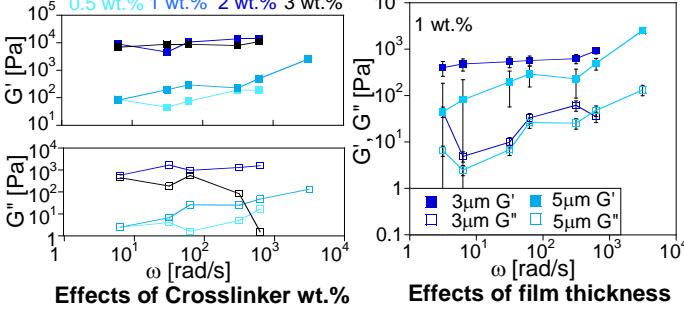
$$\frac{2k_s - \omega^2 m_s}{|x|}$$

## Viscous Fluid Calibration



- Surface tension affects amplitude
- Model predicts general behavior
- ±25% device error on viscosity above 1 Hz
- ±150 Pa error on elastic modulus above 1 Hz

## PDMS Thin Films



- Moduli grow with increasing wt.%

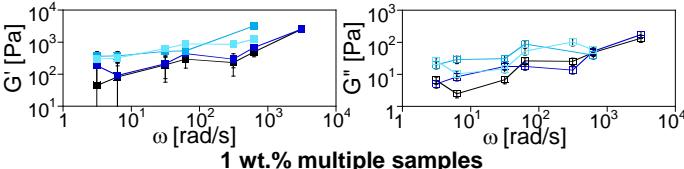
• 3 wt.% G' consistent with DMA

• G' larger for thinner film

Chen et al., J. Micromech. Microeng. (2009)

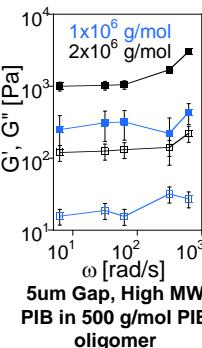
- Trends consistent with observed behavior

Chang et al., J. Polym. Sci. B (2005)



## Conclusions

- MEMs Rheometer with optical analysis can extract rheology
- Model matches observed phenomenon
- Consistent results for viscous fluids and viscoelastic thin films
- Large frequency domain, ~3 decades, with O(1)  $\mu\text{m}$  gap sizes
- Redesign of device should improve accuracy and sensitivity



Society of Rheology Annual Meeting

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